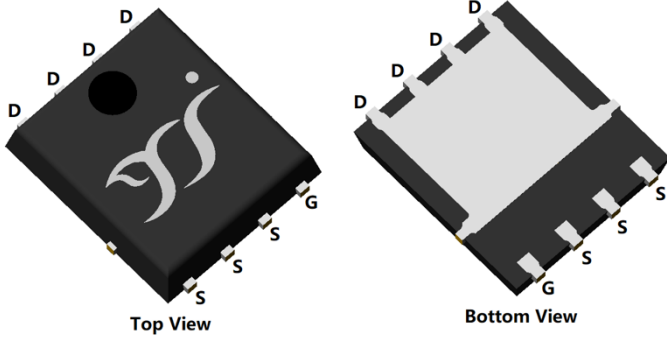
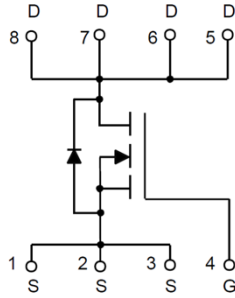


N-Channel Enhancement Mode Field Effect Transistor



Top View

Bottom View



PDFN5060-8L

Product Summary

- V_{DS} 100V
- I_D 18A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) <60mohm
- $R_{DS(ON)}$ (at $V_{GS}=4.5V$) <70mohm
- 100% EAS Tested
- 100% ∇V_{DS} Tested

General Description

- Trench Power MV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- DC-DC Converters
- Power management functions
- Backlighting

■ Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		V_{DS}	100	V
Gate-source Voltage		V_{GS}	± 20	V
Drain Current	$T_A=25^\circ C$	I_D	3.5	A
	$T_A=100^\circ C$		2	
	$T_C=25^\circ C$		18	
	$T_C=100^\circ C$		11.4	
Pulsed Drain Current ^A		I_{DM}	75	A
Total Power Dissipation ^B	$T_A=25^\circ C$	P_D	2	W
	$T_A=100^\circ C$		0.8	
	$T_C=25^\circ C$		45	
	$T_C=100^\circ C$		18	
Single Pulse Avalanche Energy ^C		E_{AS}	12.5	mJ
Thermal Resistance Junction-to-Case		$R_{\theta JC}$	2.8	$^\circ C/W$
Thermal Resistance Junction-to-Ambient ^D		$R_{\theta JA}$	60	$^\circ C/W$
Junction and Storage Temperature Range		T_J, T_{STG}	-55~+150	$^\circ C$

■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJG18N10A	F1	YJG18N10A	5000	10000	100000	13" reel



YJG18N10A

■ Electrical Characteristics (T_J=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D =250μA	100			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V			1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D =250μA	1.1	1.8	3.0	V
Static Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D =8A		49	60	mΩ
		V _{GS} = 4.5V, I _D =8A		52	70	
Diode Forward Voltage	V _{SD}	I _S =18A, V _{GS} =0V		0.8	1.2	V
Gate resistance	R _G	f=1MHz, Open drain	-	1.2	-	Ω
Maximum Body-Diode Continuous Current	I _S				18	A
Dynamic Parameters						
Input Capacitance	C _{iss}	V _{DS} =50V, V _{GS} =0V, f=1MHZ		2071		pF
Output Capacitance	C _{oss}			73		
Reverse Transfer Capacitance	C _{rss}			54		
Switching Parameters						
Total Gate Charge	Q _g	V _{GS} =10V, V _{DS} =50V, I _D =10A		51.4		nC
Gate-Source Charge	Q _{gs}			9.1		
Gate-Drain Charge	Q _{gd}			11.5		
Reverse Recovery Chrage	Q _{rr}	I _r =10A, di/dt=100A/us		35.3		
Reverse Recovery Time	t _{rr}			38		
Turn-on Delay Time	t _{D(on)}	V _{GS} =10V, V _{DD} =50V, I _D =2A R _{GEN} =3Ω		10		ns
Turn-on Rise Time	t _r			19		
Turn-off Delay Time	t _{D(off)}			42		
Turn-off fall Time	t _f			26		

A. Repetitive rating; pulse width limited by max. junction temperature.

B. P_d is based on max. junction temperature, using junction-case thermal resistance.

C. T_J=25°C, V_{DD}=50V, V_{GS}=10V, L=1mH, I_{AS}=5A.

D. The value of RθJA is measured with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in the still air environment with TA =25°C. The maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.



■ Typical Performance Characteristics

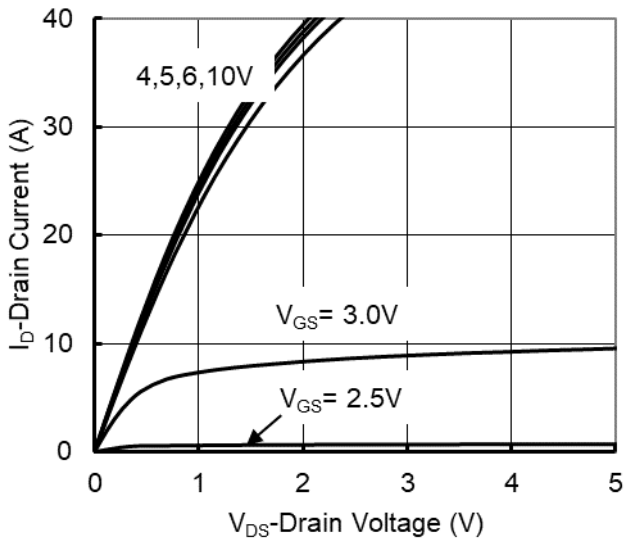


Figure 1. Output Characteristics

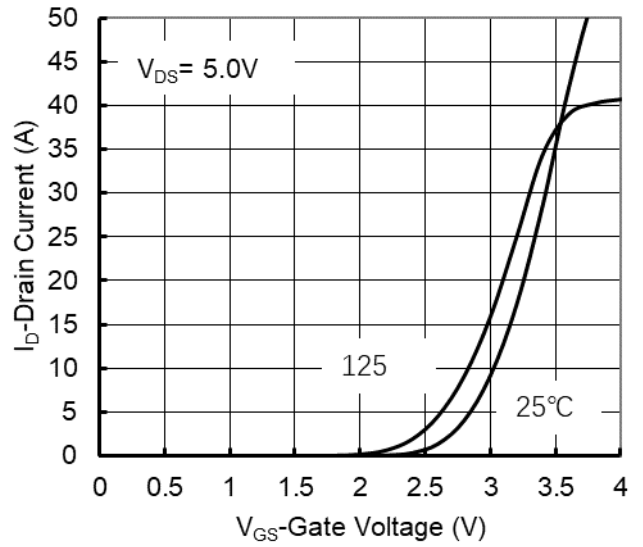


Figure 2. Transfer Characteristics

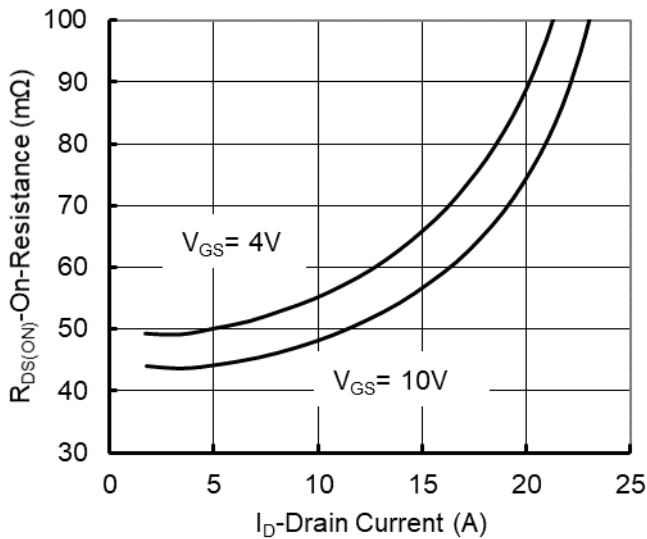


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

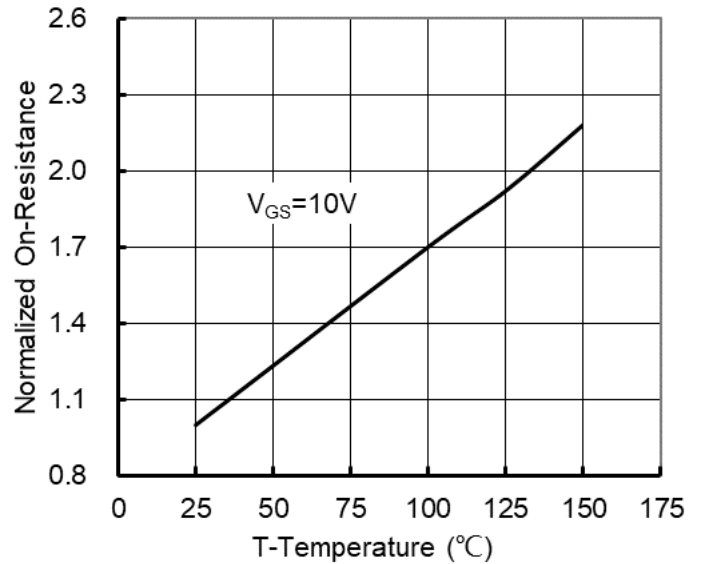


Figure 4. On-Resistance vs. Junction Temperature

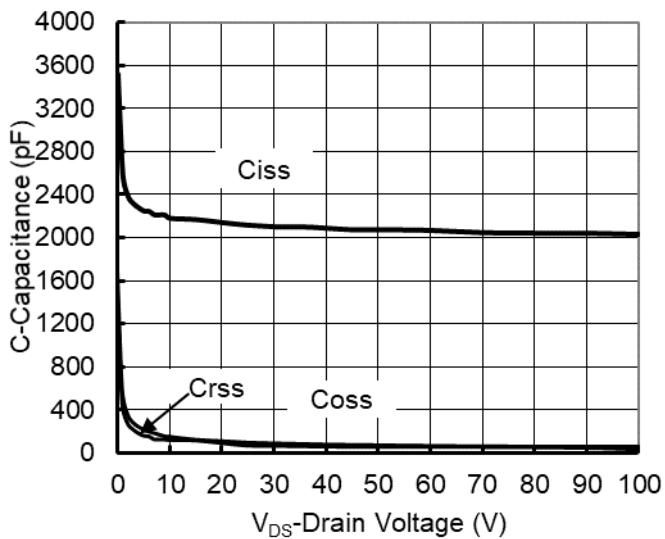


Figure 5. Capacitance Characteristics

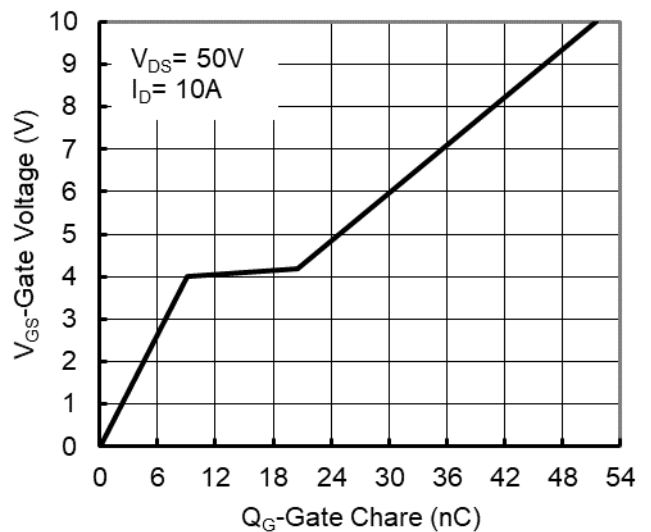


Figure 6. Gate Charge



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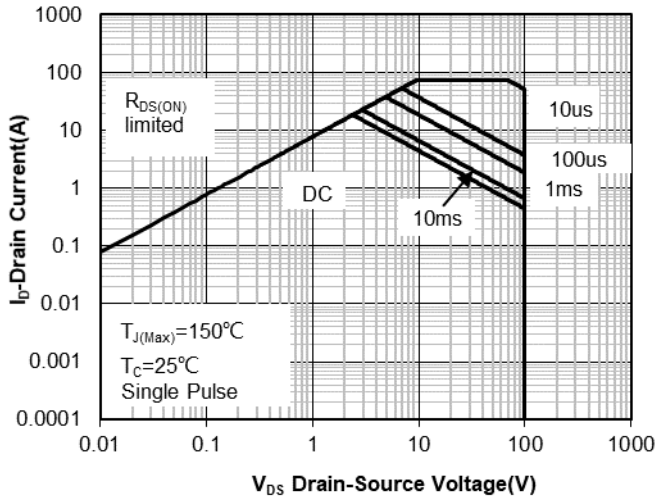


Figure 7. Safe Operation Area

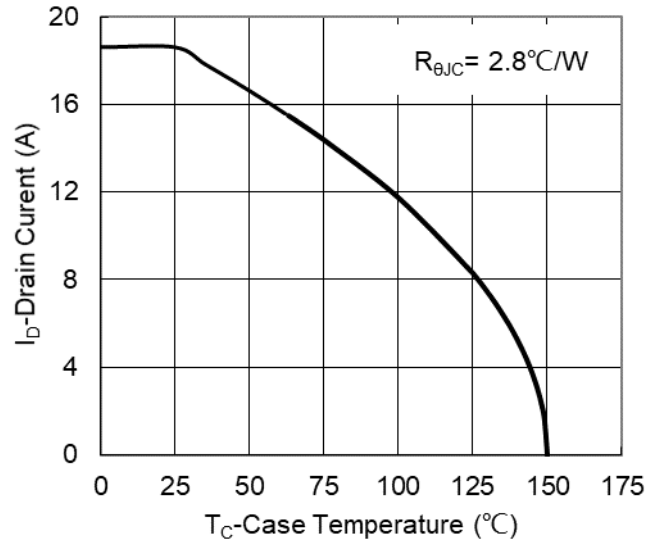


Figure 8. Maximum Continuous Drain Current vs Case Temperature

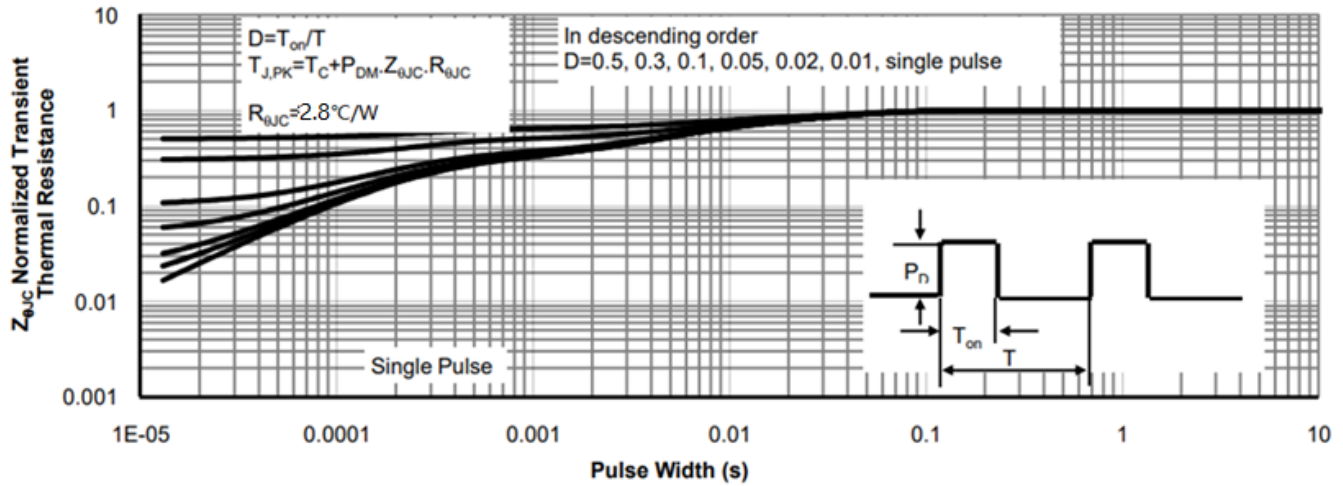
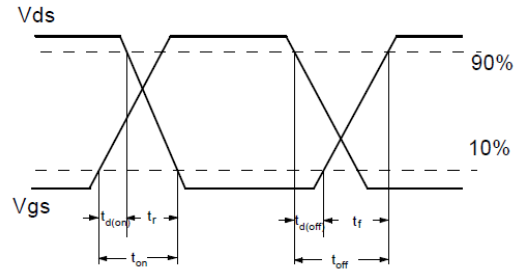
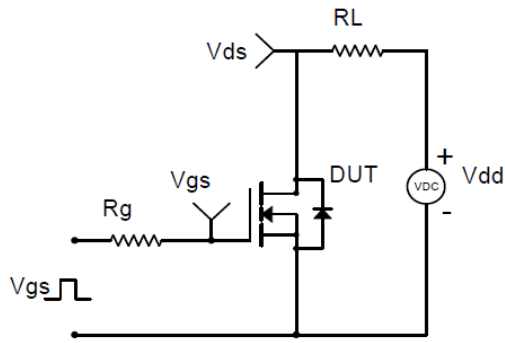
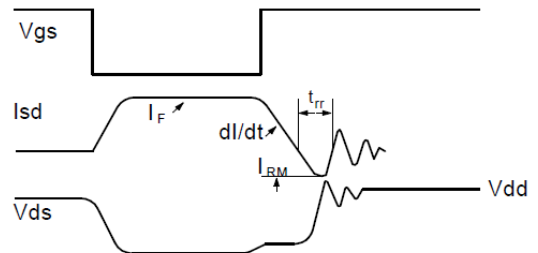
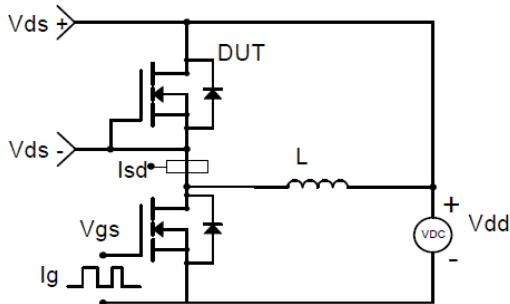


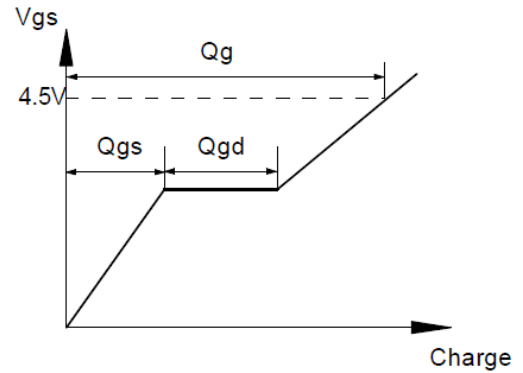
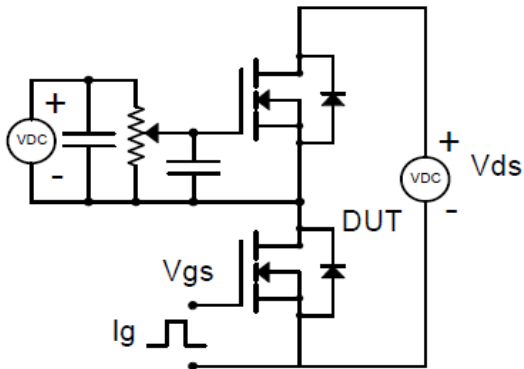
Figure 9. Normalized Maximum Transient Thermal Impedance



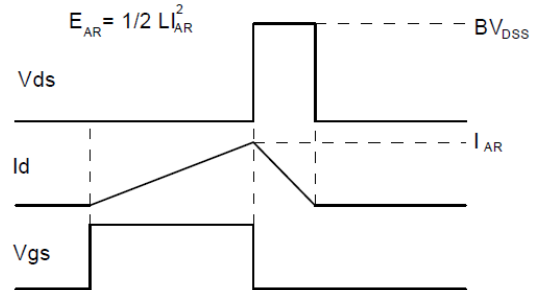
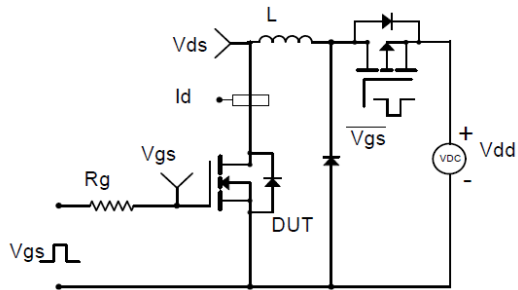
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Gate Charge Test Circuit & Waveform

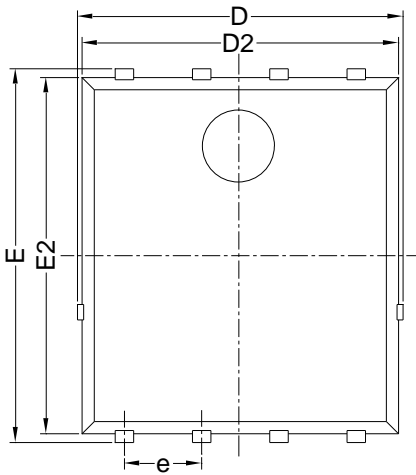


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

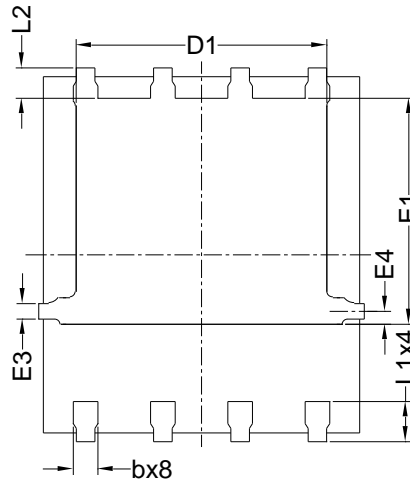


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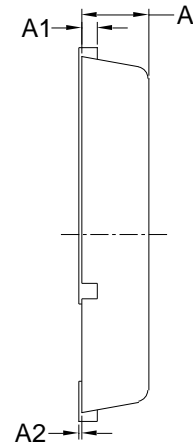
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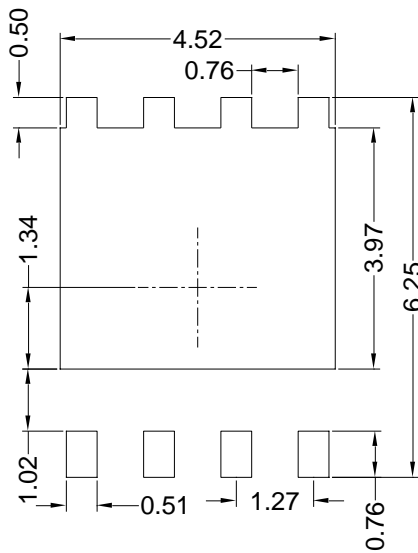
Top View
正面视图



Bottom View
背面视图



Side View
侧面视图



Suggested Solder Pad Layout
Top View

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	5.15	5.35	5.55
E	5.95	6.15	6.35
A	1.00	1.10	1.20
A1	0.254 BSC		
A2			0.10
D1	3.92	4.12	4.32
E1	3.52	3.72	3.92
D2	5.00	5.20	5.40
E2	5.66	5.86	6.06
E3	0.254 REF		
E4	0.21 REF		
L1	0.56	0.66	0.76
L2	0.50 BSC		
b	0.31	0.41	0.51
e	1.27 BSC		

Note:

1. Controlling dimension: in millimeters.
2. General tolerance: ± 0.10 mm.
3. The pad layout is for reference purposes only.



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